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# Contents

## Frontmatter

Message from the Chairs . . . . .	iii
-----------------------------------	-----

## Clone Detection and Application

### Code-to-Code Search Based on Deep Neural Network and Code Mutation

Yuji Fujiwara, Norihiro Yoshida, Eunjong Choi, and Katsuro Inoue — <i>Osaka University, Japan; Nagoya University, Japan; NAIST, Japan</i> . . . . .	1
---	---

### A Novel Approach for Detecting Type-IV Clones in Test Code

Brent van Bladel and Serge Demeyer — <i>University of Antwerp, Belgium</i> . . . . .	8
--	---

### Mining Source Code Improvement Patterns from Similar Code Review Works

Yuki Ueda, Takashi Ishio, Akinori Ihara, and Kenichi Matsumoto — <i>NAIST, Japan; Wakayama University, Japan</i> . . . . .	13
--	----

## Clone Analysis

### An Empirical Study on Clone Evolution by Analyzing Clone Lifetime

Md. Jubair Ibna Mostafa — <i>University of Dhaka, Bangladesh</i> . . . . .	20
--	----

### Tracking Method-Level Clones and a Case Study

Kyohei Uemura, Akira Mori, Eunjong Choi, and Hajimu Iida — <i>NAIST, Japan; AIST, Japan</i> . . . . .	27
---	----

### Towards Classification of Loop Idioms Automatically Extracted from Legacy Systems

Joji Okada, Takashi Ishio, Yuji Sakata, and Katsuro Inoue — <i>NTT, Japan; NAIST, Japan; Osaka University, Japan</i> . . . . .	34
--	----

Author Index . . . . .	36
------------------------	----